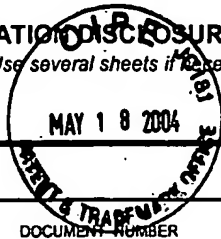


INFORMATION DISCLOSURE CITATION

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10/658,984

Jahns et al.

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September 10, 2003

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
dw	1.	5,658,423	08/19/97	ANGELL ET AL.	438	9	
	2.	5,864,773	01/26/99	BARNA ET AL.	702	85	
	3.	6,153,115	11/28/00	LE ET AL.	216	60	
	4.	6,192,826	02/27/01	SMITH, JR. ET AL.	118	723	
	5.	6,419,846	07/16/02	TOPRAC ET AL.	216	60	
	6.	6,442,445	08/27/02	BUNKOFSKE ET AL.	700	108	
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							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

dw	A.	Infineon Technologies, "USING MULTI WAY PCA (MPCA) FOR ADVANCED MONITORING AND DIAGNOSIS FOR PLASMA PROCESSING BASED ON OPTICAL EMISSION SPECTROSCOPY" by Zimpel et al., SEMATECH AEC/APC Symposium XII, (Sept. 24-28, 2000)
dw	B.	Infineon Technologies, "SUPERVISION OF PLASMA PROCESSES USING MULTI-WAY PRINCIPAL COMPONENT ANALYSIS" by Knobloch et al, IVC-15 Int'l Symposium. (Oct. 02-06, 2000)

EXAMINER

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

